International Rectifier

- Generation V Technology
- Ultra Low On-Resistance
- N-Channel Mosfet
- Surface Mount
- Available in Tape & Reel
- Dynamic dv/dt Rating
- Fast Switching
- 100% R_G Tested
- Lead-Free

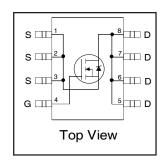
Description

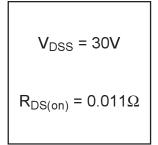
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The SO-8 has been modified through a customized leadframe for enhanced thermal characteristics and multiple-die capability making it ideal in a variety of power applications. With these improvements, multiple devices can be used in an application with dramatically reduced board space. The package is designed for vapor phase, infra red, or wave soldering techniques. Power dissipation of greater than 0.8W is possible in a typical PCB mount application.



HEXFET® Power MOSFET







Absolute Maximum Ratings

Symbol	Parameter	Max	Units	
V _{DS} Drain-to-Source Voltage		30		
V _{GS}	Gate-to-Source Voltage	± 20	V	
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	13		
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V	9.2	9.2 A 58	
I _{DM}	Pulsed Drain Current ①	58		
	Power Dissipation	2.5	W	
	Linear Derating Factor	0.02	mW/°C	
E _{AS}	Single Pulse Avalanche Energency ②	260	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns	
T _{J,} T _{STG}	Junction and Storage Temperature Range	-55 to +150	°C	

Thermal Resistance Ratings

Symbol	Parameter	Тур Мах		Units	
$R_{\theta JL}$	Junction-to-Drain Lead		20	0 0 /M	
$R_{\theta JA}$	Junction-to-Ambient ©		50	°C/W	

IRF7413PbF

Electrical Characteristics @ TJ = 25°C (unless otherwise specified)

Symbol	Parameter	Min	Тур	Max	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	30			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.034		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.011	Ω	V _{GS} = 10V, I _D = 7.3A ④
				0.018		$V_{GS} = 4.5V, I_{D} = 3.7A \oplus$
$V_{GS(th)}$	Gate Threshold Voltage	1.0		3.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
g _{fs}	Forward Transconductance	10			S	$V_{DS} = 10V, I_{D} = 3.7A$
I _{DSS}	Drain-to-Source Leakage Current			12		$V_{DS} = 30V, V_{GS} = 0V$
				25	μA	$V_{DS} = 24V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			-100	n 1	$V_{GS} = -20V$
	Gate-to-Source Reverse Leakage			100	nA	$V_{GS} = 20V$
Q _g	Total Gate Charge		52	79		$I_D = 7.3A$
Q _{gs}	Gate-to-Source Charge		6.1	9.2	nC	$V_{DS} = 24V$
Q_{gd}	Gate-to-Drain ("Miller") Charge		16	23	1	V _{GS} = 10V, See Fig. 6 and 9 ⊕
R _G	Gate Resistance			3.7	Ω	
t _{d(on)}	Turn-On Delay Time		8.6			V _{DD} = 15V
t _r	Rise Time		50		1	$I_D = 7.3A$
t _{d(off)}	Turn-Off Delay Time		52		ns	$R_G = 6.2 \Omega$
t _f	Fall Time		46			$R_G = 2.0\Omega$, See Fig. 10 \oplus
C _{iss}	Input Capacitance		1800			$V_{GS} = 0V$
C _{oss}	Output Capacitance		680		рF	$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance		240		Ī	f = 1.0MHz, See Fig. 5

Source-Drain Ratings and Characteristics

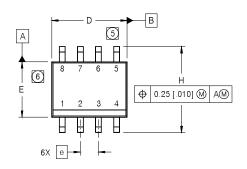
Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode)			3.1		MOSFET symbol showing the
I _{SM}	Pulsed Source Current (Body Diode) ①			58		integral reverse p-n junction diode.
V_{SD}	Diode Forward Voltage			1.0	V	$T_J = 25^{\circ}C$, $I_S = 7.3A$, $V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		74	110	ns	T _J = 25°C, I _F = 7.3A
Q _{rr}	Reverse Recovery Charge		200	300	nC	di/dt = 100A/µs ③

Notes:

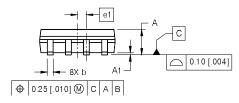
- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting $T_J = 25^{\circ}C$, L = 9.8mH $R_G = 25\Omega$, $I_{AS} = 7.3A$. (See Figure 12)
- $\label{eq:loss_def} \begin{tabular}{ll} \Im & I_{SD} \leq 7.3A, \; di/dt \leq 100A/\mu s, \; V_{DD} \leq V_{(BR)DSS}, \\ & T_{J} \leq 150 ^{\circ} C \end{tabular}$
- 4 Pulse width $\leq 300 \mu s$; duty cycle $\leq 2\%$.
- ⑤ Surface mounted on FR-4 board

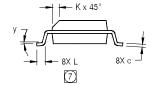
SO-8 Package Outline

Dimensions are shown in millimeters (inches)



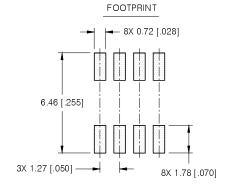
DIM	INC	HES	MILLIMETERS			
DIIVI	MIN	MAX	MIN	MAX		
Α	.0532	.0688	1.35	1.75		
A1	.0040	.0098	0.10	0.25		
b	.013	.020	0.33	0.51		
С	.0075	.0098	0.19	0.25		
D	.189	.1968	4.80	5.00		
Е	.1497	.1574	3.80	4.00		
е	.050 BASIC		1.27 BASIC			
e 1	.025 BASIC		0.635 E			
Н	.2284	.2440	5.80	6.20		
K	.0099	.0196	0.25	0.50		
L	.016	.050	0.40	1.27		
У	0°	8°	0°	8°		





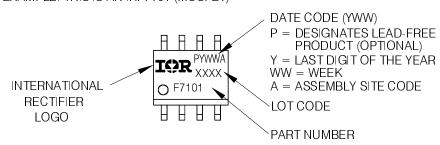
NOTES:

- 1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
- 2. CONTROLLING DIMENSION: MILLIMETER
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
- (5) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 [.006].
- (6) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 [.010].
- (7) DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.



SO-8 Part Marking

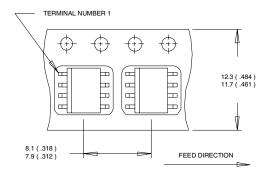
EXAMPLE: THIS IS AN IRF7101 (MOSFET)



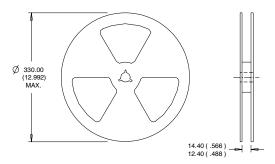


SO-8 Tape and Reel

Dimensions are shown in milimeters (inches)



- NOTES:
 1. CONTROLLING DIMENSION: MILLIMETER.
 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



- NOTES:
 1. CONTROLLING DIMENSION: MILLIMETER.
 2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Data and specifications subject to change without notice. This product has been designed and qualified for the Consumer market. Qualification Standards can be found on IR's Web site.

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